

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property  
Organization  
International Bureau



(43) International Publication Date  
28 April 2005 (28.04.2005)

PCT

(10) International Publication Number  
**WO 2005/038529 A2**

(51) International Patent Classification<sup>7</sup>:

**G03F 7/20**

(21) International Application Number:

PCT/IB2004/052145

(22) International Filing Date: 19 October 2004 (19.10.2004)

(25) Filing Language: English

(26) Publication Language: English

(30) Priority Data:  
60/512,744 20 October 2003 (20.10.2003) US

(71) Applicant (*for all designated States except US*): **KONINKLIJKE PHILIPS ELECTRONICS, N.V. [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).**

(72) Inventor; and

(75) Inventor/Applicant (*for US only*): **ZIGER, David [US/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).**

(74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS, N.V.; c/o Shannon Lester, 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).**

(81) Designated States (*unless otherwise indicated, for every kind of national protection available*): AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

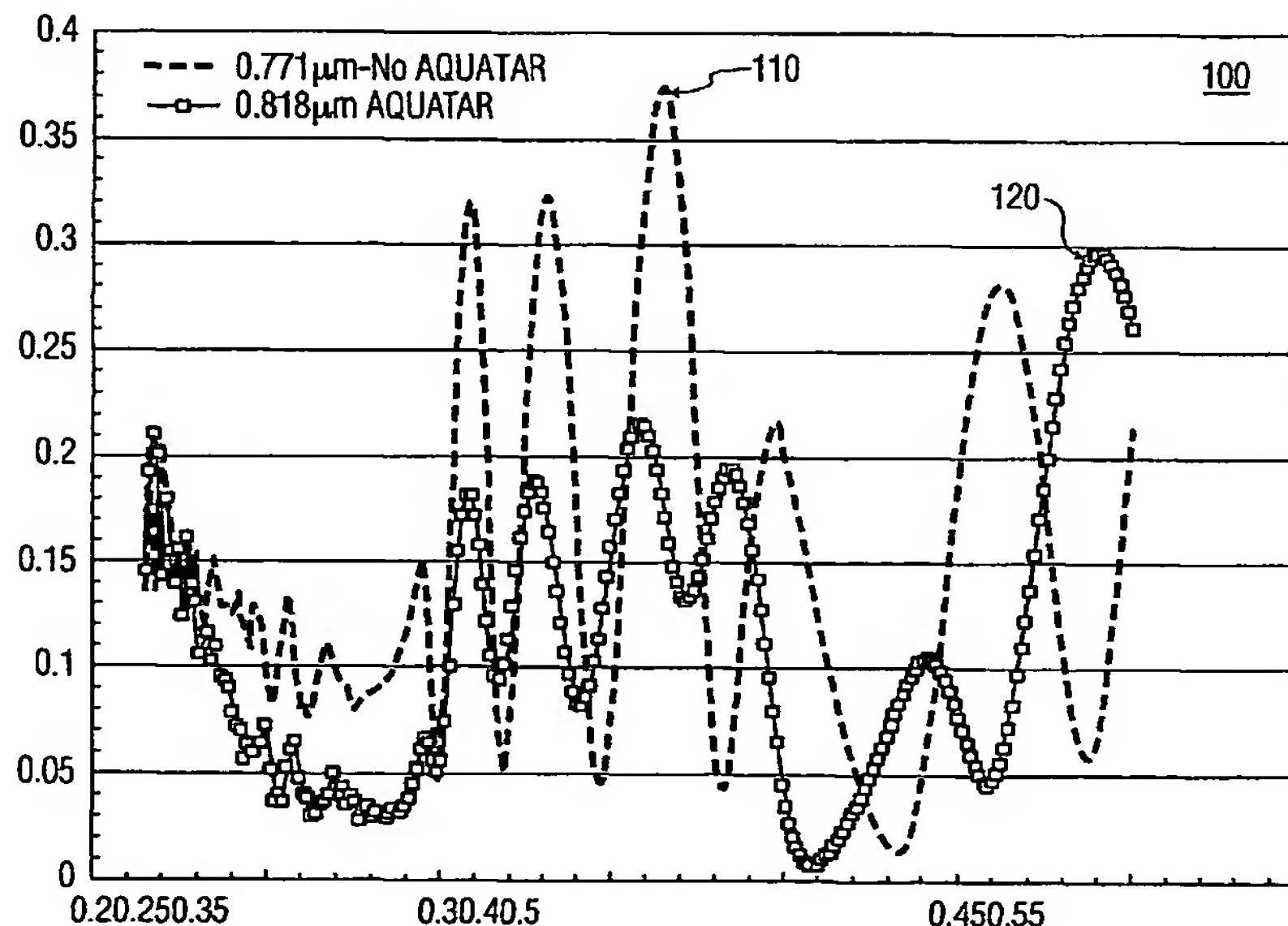
(84) Designated States (*unless otherwise indicated, for every kind of regional protection available*): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

Declarations under Rule 4.17:

- *as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ,*

[Continued on next page]

(54) Title: METHOD FOR DETERMINING RELATIVE SWING CURVE AMPLITUDE



(57) Abstract: A process (300) is disclosed to measure predetermined wavelength reflectance spectra of a resist coated wafer (305,310,315,320) at a nominal thickness. After coating, the predetermined wavelength reflectance (325,330) is measured and the peak heights and valleys in the vicinity of the predetermined wavelength are tabulated. The relative swing ratio is computed (335) as the average peak height of the spectra at the exposure wavelength. This relative swing ratio is then compared to similar computations on other processes to determine which provides the best critical dimension (CD) control.

WO 2005/038529 A2



CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE,  
EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS,  
JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA,  
MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM,  
PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ,  
TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM,  
ZW, ARIPO patent (BW, GH, GM, KE, LS, MW, MZ, NA,  
SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ,  
BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE,  
BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE,

IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI patent  
(BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE,  
SN, TD, TG)

- as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii)) for all designations

**Published:**

- without international search report and to be republished upon receipt of that report

For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.